#### 查询SN75155供应商

#### 捷多邦,专业PCB打样工厂,24小时加急出货 SN75155 LINE DRIVER AND RECEIVER

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Vcc+ 8

6 ] RTC

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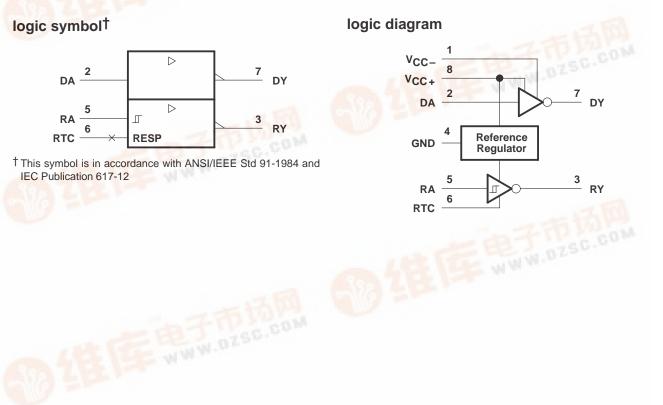
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- **D OR P PACKAGE** Meets or Exceeds the Requirements of **TOP VIEW** ANSI EIA/TIA-232-E and ITU Recommendation V.28 V<sub>CC</sub>-**10-mA Current Limited Output** DA 2 Wide Range of Supply Voltage RY [ 3  $V_{CC} = 4.5 V \text{ to } 15 V$ GND [ 4 Low Power ... 130 mW **Built-In 5-V Regulator** ZSG.COM **Response Control Provides:** Input Threshold Shifting Input Noise Filtering
  - **Power-Off Output Resistance ... 300**  $\Omega$  Typ .
  - **Driver Input TTL Compatible**

## description

The SN75155 monolithic line driver and receiver is designed to satisfy the requirements of the standard interface between data terminal equipment and data communication equipment as defined by ANSI EIA/TIA-232-E. A response control input is provided for the receiver. A resistor or a resistor and a bias voltage can be connected between the response control input and ground to provide noise filtering. The driver used is similar to the SN75188. The receiver used is similar to the SN75189A.

The SN75155 is characterized for operation from 0°C to 70°C.

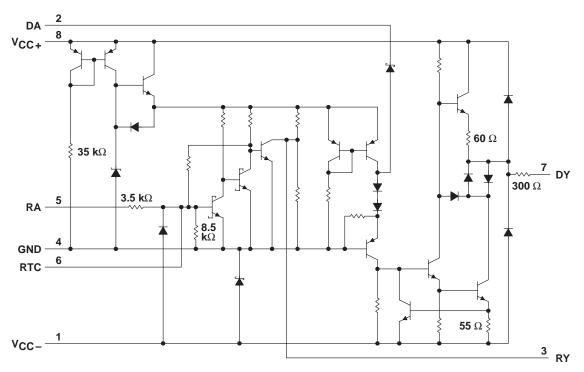




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### schematic



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC+</sub> (see Note 1)	15 V
Supply voltage, V <sub>CC</sub> (see Note 1)	–15 V
Input voltage range, VI: Driver	–15 V to 15 V
Receiver	
Output voltage range (driver), V <sub>O</sub>	
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to network ground terminal.

#### DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
D	725 mW	5.8 mW/°C	464 mW
Р	1000 mW	8.0 mW/°C	640 mW



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## recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC+</sub>	4.5	12	15	V
Supply voltage, V <sub>CC</sub> _	-4.5	-12	-15	V
Output voltage, driver, V <sub>O(D)</sub>			±15	V
Input voltage, receiver, VI(R)	-25		25	V
High-level input voltage, driver, VIH	2			V
Low-level input voltage, driver, VIL			0.8	V
Response control current			±5.5	mA
Output current, receiver, IO(R)			24	mA
Operating free-air temperature, T <sub>A</sub>	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

## total device

	PARAMETER		TEST CONDITION	S	MIN TYP <sup>†</sup>	MAX	UNIT
		V <sub>CC +</sub> = 5 V,	$V_{CC-} = -5 V$	$V_{I(D)} = 2 V,$	6.3	8.1	
ІССН+	High-level supply current V <sub>CC+</sub> = 9	V <sub>CC+</sub> = 9 V,	$V_{CC-} = -9 V$	$V_{I(R)} = 2.3 V,$	9.1	11.9	mA
		V <sub>CC+</sub> = 12 V,	$V_{CC-} = -12 V$	Output open	10.4	14	
ICCL+ Low-level supply current	V <sub>CC+</sub> = 5 V,	$V_{CC-} = -5 V$	V <sub>I(D)</sub> = 0.8 V,	2.5	3.4		
	Low-level supply current	V <sub>CC+</sub> = 9 V,	$V_{CC}$ = -9 V	$V_{I(R)} = 0.6 V,$	3.7	5.1	mA
		V <sub>CC +</sub> = 12V,	$V_{CC-} = -12 V$	Output open	4.1	5.6	
	Supply current	V <sub>CC+</sub> = 5 V,	$V_{CC} = 0$	V <sub>I(R)</sub> = 2.3 V,	4.8	6.4	mA
ICC+		V <sub>CC+</sub> = 9 V,	$V_{CC} = 0$	$V_{I(D)} = 0$	6.7	9.1	
	High-level supply current V <sub>CC</sub>	V <sub>CC+</sub> = 5 V,	$V_{CC-} = -5 V$	V <sub>I(D)</sub> = 2 V,	-2.4	-3.1	mA
Іссн-		V <sub>CC+</sub> = 9 V,	$V_{CC-} = -9 V$	$V_{I(R)} = 2.3 V$	-3.9	-4.9	
		V <sub>CC+</sub> = 12 V,	$V_{CC-} = -12 V$	Output open	-4.8	-6.1	
		V <sub>CC+</sub> = 5 V,	$V_{CC-} = -5 V$	V <sub>I(D)</sub> = 0.8 V,	-0.2	-0.35	
ICCL-		V <sub>CC+</sub> = 9 V,	VCC = -9 V	$V_{I(R)} = 0.6 V,$	-0.25	-0.4	mA
		V <sub>CC +</sub> = 12 V,	$V_{CC-} = -12 V$	Output open	-0.27	-0.45	

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .



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# electrical characteristics over recommended operating free-air temperature range, $V_{CC+} = 12 V$ , $V_{CC-} = -12 V$ (unless otherwise noted)

#### driver section

	PARAMETER	TES	<b>CONDITIONS</b>		MIN	түр†	MAX	UNIT
			V <sub>CC+</sub> = 5 V,	$V_{CC-} = -5 V$	3.2	3.7		
∨он	High-level output voltage	$V_{IL} = 0.8 \text{ V}, \text{ R}_{L} = 3 \text{ k}\Omega$	V <sub>CC+</sub> = 9 V,	VCC - = -9 V	6.5	7.2		V
			V <sub>CC+</sub> = 12 V,	$V_{CC-} = -12 V$	8.9	9.8		
			V <sub>CC+</sub> = 5 V,	$V_{CC-} = -5 V$		-3.6	-3.2	
VOL	Low-level output voltage (see Note 2)	$V_{IH} = 2 V$ , $R_L = 3 k\Omega$	V <sub>CC+</sub> = 9 V,	VCC - = -9 V		-7.1	-6.4	V
			V <sub>CC+</sub> = 12 V,	$V_{CC-} = -12 V$		-9.7	-8.8	
Чн	High-level input current	VI = 7 V					5	μA
ЧL	Low-level input current	V <sub>I</sub> = 0				-0.73	-1.2	mA
IOS(H)	High-level short-circuit output current	$V_{I} = 0.8 V, V_{O} = 0$			-7	-12	-14.5	mA
IOS(L)	Low-level short-circuit output current	$V_{I} = 2 V, \qquad V_{O} = 0$			6.5	11.5	15	mA
rO	Output resistance with power off	$V_{O} = -2 V$ to 2 V				300		Ω

### receiver section (see Figure 1)

	PARAMETER		TEST CONDITIO	ONS	MIN	TYP†	MAX	UNIT
V <sub>IT+</sub>	Positive-going input threshhold voltage				1.2	1.9	2.3	V
$V_{IT-}$	Negative-going input threshhold voltage				0.6	0.95	1.2	V
V <sub>hys</sub>	Hystresis voltage (V <sub>IT +</sub> – V <sub>IT –</sub> )				0.6			V
	High-level output voltage	$V_{I} = 0.6 V_{,}$	$V_{CC+} = 5 V,$	$V_{CC-} = -5 V$	3.7	4.1	4.5	
Vaun		I <sub>OH</sub> = 10 μA	V <sub>CC+</sub> = 12 V,	$V_{CC-} = -12 V$	4.4	4.7	5.2	V
VO(H)		$V_{I} = 0.6 V,$ $I_{OH} = 0.4 mA$	V <sub>CC+</sub> = 5 V,	$V_{CC-} = -5 V$	3.1	3.4	3.8	
			V <sub>CC+</sub> = 12 V,	$V_{CC-} = -12 V$	3.6	4	4.5	
VO(L)	Low-level output voltage	VI = 2.3 V,	I <sub>OL</sub> = 24 mA			0.2	0.3	V
I	Ligh lovel input ourrest	VI = 2 5 V			3.6	6.7	10	mA
ΙН	High-level input current	VI = 3 V			0.43	0.67	1	mA
L.					-3.6	-6.7	-10	mA
ΙL	Low-level input current	V <sub>I</sub> = -3 V			-0.43	-0.67	-1	mA
los	Short-circuit output current	$V_{I} = 0.6 V$				-2.8	-3.7	mA

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .

NOTE 2: The algebraic limit system, in which the more positive (less negative) limit is designated as maximum, is used in this data sheet for logic voltage levels only (e.g., if -8.8 V is the maximum, the typical value is a more negative value).



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# switching characteristics over recommended operating free-air temperature range, $V_{CC+} = 5 V$ , $V_{CC-} = -5 V$ , $C_L = 50 pF$ (unless otherwise noted)

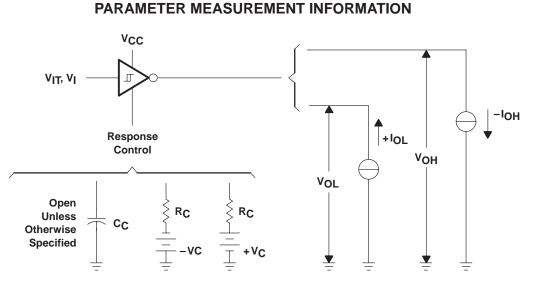
## driver section (see Figure 2)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low- to high level output	$R_1 = 3 k\Omega$		250	480	20
<b>t</b> PHL	Propagation delay time, high- to low level output	$K = 3 K \Sigma$		80	150	ns
	Output rise time	$R_L = 3 k\Omega$		67	180	ns
τ <sub>r</sub>	Output lise time	$R_L = 3 k\Omega$ to 7 k $\Omega$ , $C_L = 2500 pF$		2.4	3	μs
+.	Output fall time	$R_L = 3 k\Omega$		48	160	ns
t <sub>f</sub>		$R_L = 3 \text{ k}\Omega \text{ to } 7 \text{ k}\Omega, \qquad C_L = 2500 \text{ pF}$		1.9	3	μs

## receiver section (see Figure 3)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low- to high level output	P: - 400 O		175	245	20
t <sub>PHL</sub>	Propagation delay time, high- to low level output	R <sub>L</sub> = 400 Ω		37	100	ns
tr	Output rise time	R <sub>L</sub> = 400 Ω		255	360	ns
t <sub>f</sub>	Output fall time	R <sub>L</sub> = 400 Ω		23	50	ns

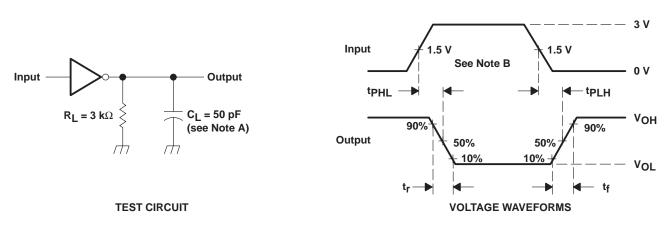
<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ .







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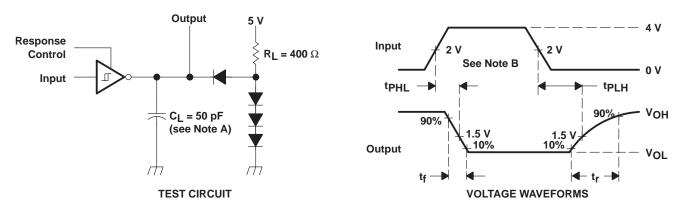


### PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

B. The input waveform is supplied by a generator with the following characteristics:  $Z_0 = 50 \Omega$ ,  $t_w = 1 \mu s$ ,  $t_f \le 10 ns$ .





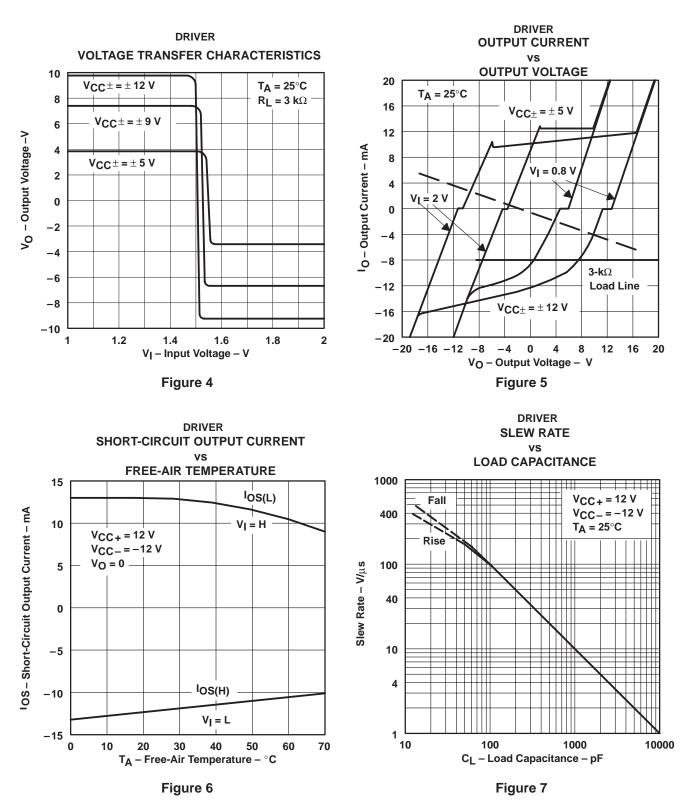
NOTES: A. CL includes probe and jig capacitance.

B. The input waveform is supplied by a generator with the following characteristics:  $Z_{O} = 50 \Omega$ ,  $t_{W} = 1 \mu$ s,  $t_{f} \le 10 ns$ .

## Figure 3. Receiver Section Switching Test Circuit and Voltage Waveforms



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**TYPICAL CHARACTERISTICS** 



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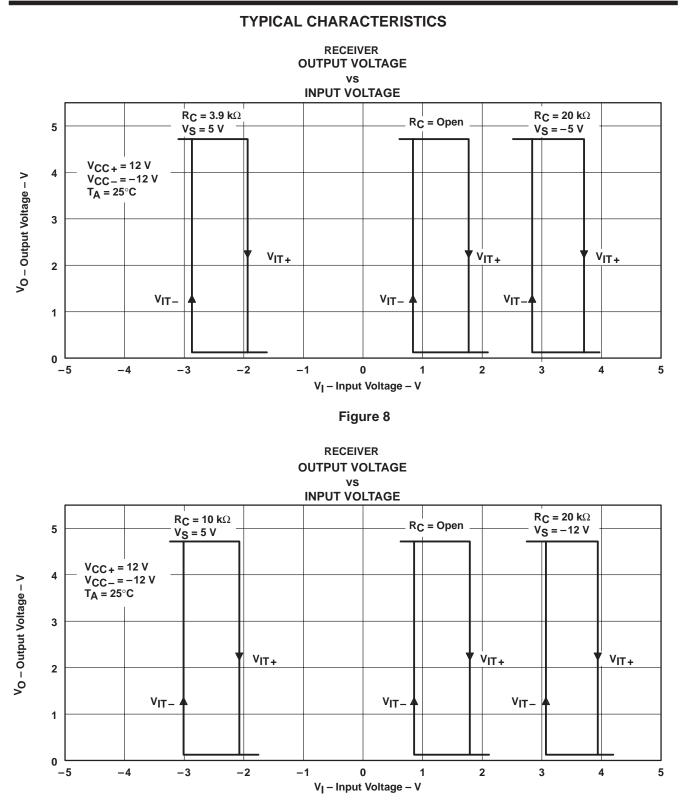
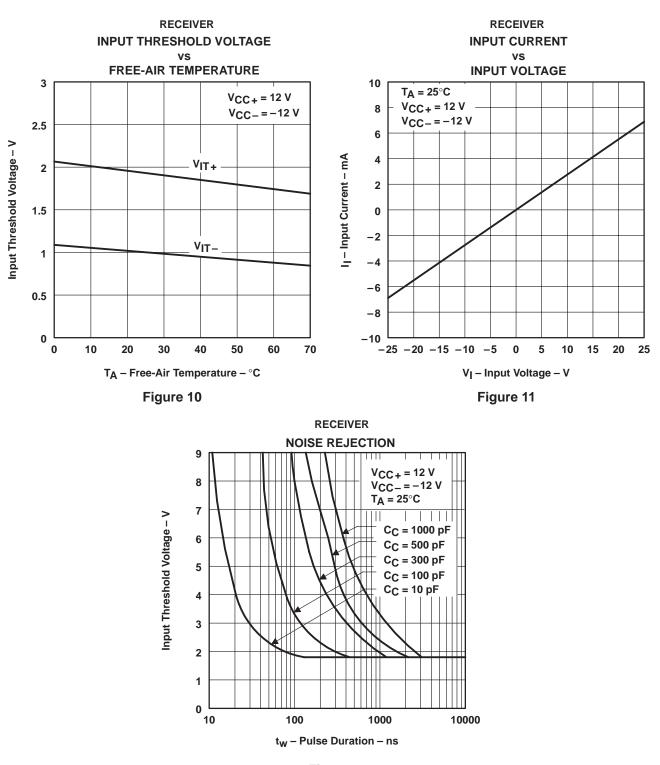


Figure 9



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**TYPICAL CHARACTERISTICS** 





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